

<b>Notice of References Cited</b>	Application/Control No. 09/658,241		Applicant(s)/Patent Under Reexamination HOHNSTEIN ET AL.	
	Examiner TAN TRINH		Art Unit 2618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0195017	10-2003	Chen et al.	455/562.1
*	B	US-2001/0031648	10-2001	Proctor et al.	455/562
*	C	US-6,473,411	10-2002	Kumaki et al.	370/331
*	D	US-6,141,335	10-2000	Kuwahara et al.	370/342
*	E	US-2001/0014614	08-2001	LAUTENSCHLAGER et al.	455/553
*	F	US-2001/0046865	11-2001	HILDEBRAND et al.	455/447
*	G	US-2006/0195643	08-2006	Carey, John A.	710/240
*	H	US-2001/0004583	06-2001	Uchida, Yoshinori	455/12.1
*	I	US-2004/0259597	12-2004	Gothard et al.	455/562.1
*	J	US-2002/0013150	01-2002	McKenna et al.	455/430
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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